## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10580610	CID, PAU	
Examiner	Art Unit	
Loewe, Sun Jae Y	1626	

SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES					
Search Notes	Date	Examiner			
restriction requirement	1-26-2008	sl			

INTERFERENCE SEARCH					
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